

Member State of OIML
Japan



OIML Certificate No
R76/1992-JP1-06.02

OIML CERTIFICATE OF CONFORMITY

Issuing authority

Name: National Institute of Advanced Industrial Science and Technology
Address: 1-3-1, Kasumigaseki, Chiyoda-ku, TOKYO, 100-8921, Japan
Person responsible: Hiroyuki Yoshikawa

Applicant

Name: A&D Company, Limited
Address: 3-23-14 Higashi-ikebukuro, Toshima-ku, Tokyo 170-0013, JAPAN

Manufacturer of the certified pattern

Name: A&D SCALES CO.,LTD.
Address: 162-4 INSAN-NI, DEOGSAN-MYEON, JINCHEON-GUN,
CHUNGCHONGBUG-DO, KOREA

Identification of the certified pattern:

Type FG.../AD-6208...
Further characteristics see page 2

This certificate attests the conformity of the above-mentioned pattern (represented by the samples identified in the associated test report) with the requirements of the following Recommendation(s) of the International Organization of Legal Metrology (OIML):

R76-1, edition 1992, including amendment 1 (1994),
for accuracy class **III**

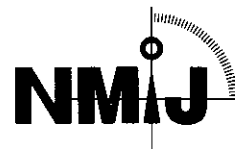
This certificate relates only to the metrological and technical characteristics of the pattern of the instrument concerned, as covered by the relevant OIML International Recommendation(s).

This certificate does not bestow any form of legal international approval.

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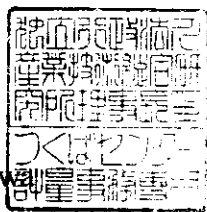
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The conformity was established by tests described in the associated test report N° 06-01-A/R76 (58 pages) and N° 06-01-B/R76 (32 pages).

The Issuing Authority

The OIML member



Dr. H. Yoshikawa
President
Feb 27 2006

Dr. Y. Miki
Feb 27 2006

Characteristics:

Type	FG...	AD-6208...	
Accuracy class	III	III	
Max	30 kg ~ 150 kg	150 kg	200 kg
e	10 g ~ 50 g	50 g	100 g
n	≤ 3000	≤ 3000	≤ 2000
Min	200 g ~ 1 kg	1 kg	2 kg
Tare-balancing range	≤ 100% of Max subtractive		
Temperature range	-10 °C / 40 °C		

Important note: Apart from the mention of certificate's reference number and the name of the OIML Member State in which the certificate was issued, partial quotation of the certificate or of the associated test report is not permitted, though they may be reproduced in full.